L Number	Hits	Search Text	DB	Time stamp
1	0	275/292.ccls. and transfer and reset and	USPAT	2003/12/03
2	130	drain 257/292.ccls. and transfer and reset and	USPAT	14:54 2003/12/03
3	80	drain 257/292.ccls. and (transfer with reset)	USPAT	14:55
4		and drain		15:43
4	4	257/292.ccls. and (transfer with reset) and drain and deplete	USPAT	2003/12/03 15:43
_	370	348/241.ccls.	USPAT	2003/11/25 12:40
-	1	5953060.pn.	USPAT	2003/11/24 11:52
-	1	4274113.pn.	USPAT	2003/11/24 11:53
-	0	348/241.ccls. and feedback adj conversion adj circuit	USPAT	2003/11/24
-	4	348/241.ccls. and feedback with impedance	USPAT	2003/11/24 14:10
-	0	348/241.ccls. and reset with selection	USPAT	2003/11/24
-	9	with on 348/241.ccls. and reset with selection	USPAT	14:11 2003/11/24
_	6	348/241.ccls. and reset with detection	USPAT	14:48 2003/11/24
_	4	with amplifier 348/241.ccls. and (reset with detection	USPAT	14:49 2003/11/24
_	1	with amplifier) and sampling 348/241.ccls. and cathode and	USPAT	14:57 2003/11/24
_	12	concentration 348/241.ccls. and reset with conductive	USPAT	15:17 2003/11/24
_	9	348/241.ccls. and light with conductive	USPAT	16:10 2003/11/24
_	0	348/241.ccls. and deplete with conductive	USPAT	16:17 2003/11/24
_	0	348/241.ccls. and depleted with	USPAT	16:17 2003/11/24
_	5	conductive 348/241.ccls. and well with conductive	USPAT	16:18 2003/11/24
_	0	conductive with semiconducter with region	USPAT	16:32 2003/11/24
	_	with cathode with depleted		16:33
_	0	conductive with semiconductor with region with cathode with depleted	USPAT	2003/11/24
_	0	conductive with semiconductor with region with cathode with deplete	USPAT	2003/11/24 16:34
_	0	conductive with semiconducter with region with cathode with deplete	USPAT	2003/11/24 16:34
_	0	semiconducter with region with cathode with deplete	USPAT	2003/11/24 16:34
_	8	semiconductor with region with cathode with deplete	USPAT	2003/11/24 16:34
-	504	gate with electrode with cathode with region	USPAT	2003/11/25
-	55	gate with electrode with cathode with region with drain	USPAT	2003/11/25
-	191864	reset withgate with electrode with cathode with region with drain	USPAT	2003/11/25 12:44
-	1	reset with gate with electrode with cathode with region with drain	USPAT	2003/11/25
_	372	348/241.ccls.	USPAT	12:44 2003/11/25
_	174	348/241.ccls. and reset	USPAT	12:49 2003/11/25
-	21	(348/241.ccls. and reset) and cathode	USPAT	12:49 2003/11/25
_	5	((348/241.ccls. and reset) and cathode)	USPAT	12:50 2003/11/25
_	5	and reset with cathode 348/241.ccls. and reset with cathode	USPAT	12:55 2003/11/25
	L			12:57

		_		
-	81	(reset with cathode) with electrode	USPAT	2003/11/25
				12:59
-	275	(reset with cathode) with electrode witrh	USPAT	2003/11/25
		conentration		12:59
_	530471	(reset with cathode) with electrode witrh	USPAT	2003/11/25
		concentration		12:59
-	0	(reset with cathode) with electrode with	USPAT	2003/11/25
		concentration		13:00
-	1	(reset with cathode) with electrode same	USPAT	2003/11/25
		concentration		13:00
-	823	reset with cathode	USPAT	2003/11/25
				13:01
-	35	(gate with electrode with cathode with	USPAT	2003/11/25
		region) with concentration		13:01
-	0	((reset with cathode) with electrode)	USPAT	2003/11/25
		with concentration		13:01
-	1	(reset with cathode) same (concentration)	USPAT	2003/11/25
				13:06
-	1	(reset with cathode) same (concentration)	USPAT;	2003/11/25
			US-PGPUB;	13:07
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	11	(reset with cathode) and (drain with	USPAT;	2003/11/25
		concentration)	US-PGPUB;	13:07
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	